

Application/Control No.	Applicant(s)/Patent under Reexamination
10/642,896	TAKANO ET AL.
Examiner	Art Unit
Frank Duong	2616

	SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST SEARCH (see printout)	5/16/2007	FD		
INVENTORSHIP SEARCH (see printout)	5/16/2007	FD		
IEEE/INTERNET SEARCH	5/16/2007	FD		